

# TECHNICAL SPECIFICATION

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**Nanomanufacturing - Key control characteristics -  
Part 11-1: Electromagnetic compatibility - Shielding effectiveness of  
nanomaterials: near-field probe method**

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IEC Secretariat  
3, rue de Varembe  
CH-1211 Geneva 20  
Switzerland

Tel.: +41 22 919 02 11  
[info@iec.ch](mailto:info@iec.ch)  
[www.iec.ch](http://www.iec.ch)

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**Nanomanufacturing -  
Key control characteristics -  
Part 11-1: Electromagnetic compatibility -  
Shielding effectiveness of nanomaterials: near-field probe method**

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The text of this Technical Specification is based on the following documents:

| Draft       | Report on voting |
|-------------|------------------|
| 113/872/DTS | 113/909/RVDTS    |

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Specification is English.